

Notice of References Cited

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	M	US-			

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NON-PATENT DOCUMENTS

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	U	The IEEE Standard Dictionary of Electrical and Electronic Terms, IEEE, Sixth Edition, Page 1116
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